EV318282061

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No
Priority Filing Date January 24, 2002
Inventor
Assignee Micron Technology, Inc.
Priority Group Art Unit
Priority Examiner
Attorney's Docket No MI22-2379
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, copending application of the above-identified application. The above-identified application is a divisional application of co-pending Application Serial No. 10/057,711, filed January 24, 2002, upon which the above-identified application relies for a priority date under 35 U.S.C. §120. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2).

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 7-3/-03

D. Brent Kenady

Reg. No. 40,045 Customer No. 021567

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